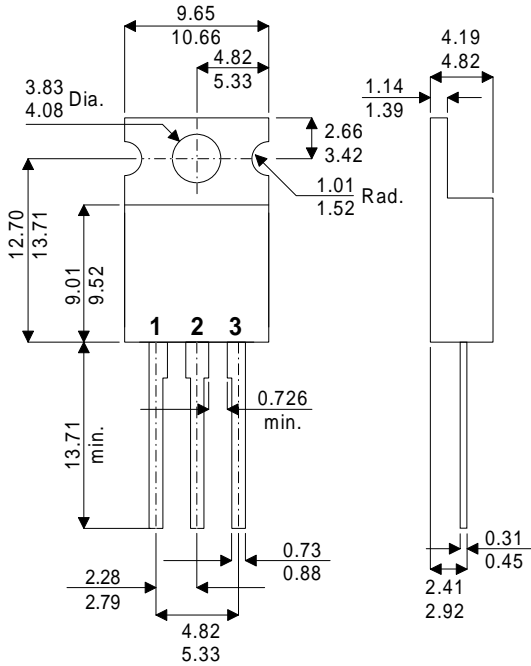


MECHANICAL DATA
Dimensions in mm



SILICON EPITAXIAL BASE
PNP POWER TRANSISTORS

PNP Transistors in a plastic TO-220 package.

With their NPN complements BD949 ; 951 ; 953 and 955 they are intended for use in a wide range of power amplifiers and for switching applications.

TO-220AB TO220 Plastic Package

Pin 1 - Base Pin 2 - Collector Pin 3 - Emitter

Collector connected to Mounting Base.

ABSOLUTE MAXIMUM RATINGS

($T_{case} = 25^{\circ}C$ unless otherwise stated)

		BD950	BD952	BD954	BD956
V_{CBO}	Collector - Base Voltage	-60V	-80V	-100V	-120V
V_{CEO}	Collector - Emitter Voltage	-60V	-80V	-100V	-120V
V_{EBO}	Emitter - Base Voltage		-5V		
I_C	Collector Current		-5A		
I_{CM}	Peak Collector Current		-8A		
P_{tot}	Total Power Dissipation		40W		
T_{stg}	Storage Temperature Range		-65 to 150°C		
T_J	Maximum Junction Temperature		150°C		

ELECTRICAL CHARACTERISTICS ($T_{case} = 25^{\circ}C$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{BE}^* Base - Emitter Voltage ¹	$I_C = -2A$ $V_{CE} = -4V$			1.4	V
$V_{CE(sat)}^*$ Collector - Emitter Saturation Voltage	$I_C = -2A$ $I_B = -0.2A$			1	V
I_{CBO} Collector Cut-off Current	$I_E = 0$ $V_{CB} = V_{CBO(MAX)}$			0.1	mA
	$I_E = 0$ $V_{CB} = \frac{1}{2}V_{CBO(MAX)}$ $T_J = 150^{\circ}C$			2	
	$I_B = 0$ $V_{CE} = \frac{1}{2}V_{CEO(MAX)}$			0.5	
I_{EBO} Emitter Cut-off Current	$I_C = 0$ $V_{EB} = -5V$			1	mA
h_{FE}^* DC Current Gain	$I_C = -0.5A$ $V_{CE} = -4V$	40			—
	$I_C = -2A$ $V_{CE} = -4V$	20			
f_T Transition Frequency	$I_C = -0.5A$ $V_{CE} = -4V$ $f = 1MHz$	3			MHz
t_{ON} Turn-on Time	$I_{C(ON)} = 1A$ $-I_{B(ON)} = I_{B(OFF)} = 0.1A$		0.1		μs
t_{OFF} Turn-off Time			0.4		

* Pulse Test: $t_p \leq 300\mu s$, $\delta < 2\%$

Note 1 V_{EB} decreases by about 2.3mV/K with increasing temperature.

THERMAL CHARACTERISTICS

$R_{\theta J-MB}$ Thermal Resistance Junction to Mounting Base			3.12	K/W
$R_{\theta JA}$ Thermal Resistance Junction to Ambient			70	K/W

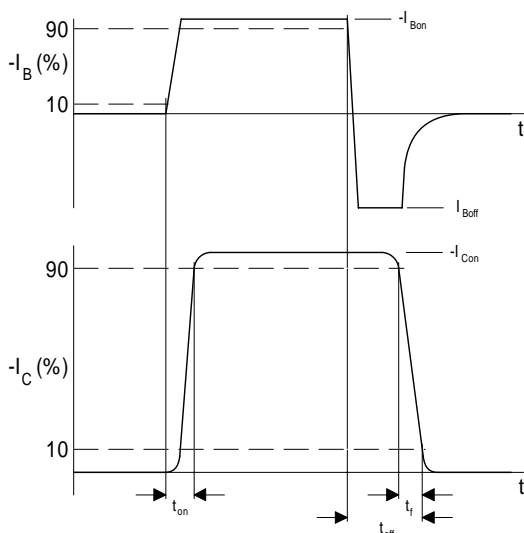


Fig. 1 Switching times waveforms.

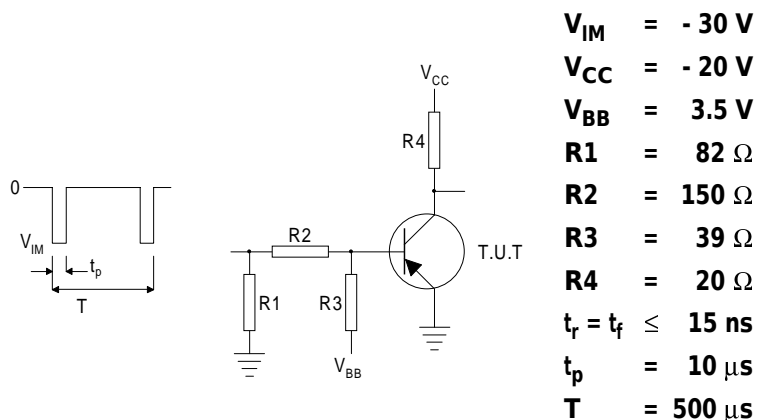


Fig. 2 Switching times test circuit.